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Cont but measurement is performed by means of a binary search method
from the next position.--

In the claims:

Please amend claim 4 by replacing it with the like-numbered claim hereinbelow. Markups are provided at the end of this response showing the changes made by the amendment.

4. (Amended) A semiconductor device test method for detecting a pass/fail threshold within a prescribed test range for a semiconductor device based on a binary search method, comprising:

a first step of setting either an upper-limit value or a lower-limit value of said test range as a pass value and the other limit value as a fail value;

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a second step of setting a measurement position in accordance with the binary search method, using said pass value and said fail value;

a third step of performing a prescribed measurement on said semiconductor device at said measurement position set in said second step;

a fourth step of setting said pass value equal to the measurement position set in said second step if the measurement result obtained in said third step is a pass, or setting said fail value equal to the measurement position set in said second step if said measurement result is a fail; and